

# NANOSCALE RESEARCH FACILITY

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## External User Charges

SI No .	Equipment	Details of Measurement	Sample Type	Charges per Sample(Academic Institute) Rs.	Charges per Sample(Industrial) Rs.
1.	XRD	XRD pattern (one scan)(20°to 80° scan)	Powder/Bulk	500	2000
		XRD pattern (one scan) (20° to 80° scan)	Film	500	2500
2.	Tabletop SEM (without coating)	Surface Morphology	Film/Bulk pallet	500	2000
3.	SEM (EDAX)	Element Analysis	Film/Bulk	500	2000
		Element Scan	Film/Bulk	1000	3000
4.	Thickness Monitor	Stylus Type	Film with a step formed in the coating	500	1000
5.	Photoluminescence(PL)	Excitation 325,510,785nm Scan range 300nm - 800nm	Film	500	2000
6.	Raman	1cm <sup>-1</sup> resolution 530nm excitation	Bulk pallet/Film	500	2000
7.	UV-VIS	Total reflectance Wavelength range 250-1100nm	Film	500	1000
		250-2500nm	Film	700	1500
		Diffuse reflectance Wavelength range 250-1100nm	Film	500	1000
		250-2500nm	Film	700	1500
		Transmittance/ Absorbance Wavelength range 250-1100nm	Film/Solution	500	1000
		250-2500nm	Film/Solution	700	1500
8.	FTIR	ATR and FTIR (400 4000 wave numbers)	Powder, Polymer film, KBR pallet	500	2000
9.	AFM	STM,AFM, KPFM,MFM,modes conducting AFM,STHM	Film	500	2000